RELIABILITY REPORT

FOR

MAX6725KALTD3+

PLASTIC ENCAPSULATED DEVICES

September 20, 2010

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Approved by
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Quality Assurance
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Conclusion

The MAX6725KALTD3+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim"s continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim"s quality and reliability standards.

Table of Contents

I. Device Description

A. General

The MAX6715-MAX6729 are ultra-low-voltage microprocessor (µP) supervisory circuits designed to monitor two or three system power-supply voltages. These devices assert a system reset if any monitored supply falls below its factory-trimmed or adjustable threshold and maintain reset for a minimum timeout period after all supplies rise above their thresholds. The integrated dual/triple supervisory circuits significantly improve system reliability and reduce size compared to separate ICs or discrete components. These devices monitor primary supply voltages (VCC1) from 1.8V to 5.0V and secondary supply voltages (VCC2) from 0.9V to 3.3V with factory-trimmed reset threshold voltage options (see *Reset Voltage Threshold Suffix Guide*). An externally adjustable RSTIN input option allows customers to monitor a third supply voltage down to 0.62V. These devices are guaranteed to be in the correct reset output logic state when either VCC1 or VCC2 remains greater than 0.8V. A variety of push-pull or open-drain reset outputs along with watchdog input, manual reset input, and power-fail input/output features are available (see *Selector Guide*). Select reset timeout periods from 1.1ms to 1120ms (min) (see *Reset Timeout Period Suffix Guide*). The MAX6715-MAX6729 are available in small 5, 6, and 8-pin SOT23 packages and operate over the -40°C to +85°C temperature range.

II. Manufacturing Information

A. Description/Function:	Dual/Triple Ultra-Low-Voltage SOT23 µP Supervisory Circuits
B. Process:	B8
C. Number of Device Transistors:	
D. Fabrication Location:	California or Texas
E. Assembly Location:	Thailand
F. Date of Initial Production:	January 26, 2002

III. Packaging Information

A. Package Type:	8-pin SOT23
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Non-conductive
E. Bondwire:	Au (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-9000-2052
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Jb:	112°C/W
K. Single Layer Theta Jc:	80°C/W
L. Multi Layer Theta Ja:	N/A
M. Multi Layer Theta Jc:	N/A

IV. Die Information

A. Dimensions:	32 X 57 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al/0.5%Cu with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	0.8 microns (as drawn)
F. Minimum Metal Spacing:	0.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:	Don Lipps (Manager, Reliability Engineering) Bryan Preeshl (Managing Director of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% For all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4340 \times 45 \times 2}$$ (Chi square value for MTTF upper limit)

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$\lambda = 24.4 \times 10^{-9}$

$\lambda = 24.4$ F.I.T. (60% confidence level @ 25°C)

The following failure rate represents data collected from Maxim"s reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at http://www.maxim-ic.com/qa/reliability/monitor. Cumulative monitor data for the B8 Process results in a FIT Rate of 0.06 @ 25C and 0.99 @ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing (lot T7H6CQ002B, D/C 0631)

The MS68-6 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2500 per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/-250mA.

Table 1
Reliability Evaluation Test Results

MAX6725KALTD3+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)					
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	45	0	S0000A073F, D/C 0513

Note 1: Life Test Data may represent plastic DIP qualification lots.